

<b>Notice of References Cited</b>	Application/Control No. 10/525,244	Applicant(s)/Patent Under Reexamination HOSHI ET AL.	
	Examiner G. Nagesh Rao	Art Unit 1722	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,117,231	09-2000	Fusegawa et al.	117/30
*	B	US-7,077,726	07-2006	Pietsch et al.	451/41
*	C	US-2001/0041258	11-2001	Passek et al.	428/332
*	D	US-2003/0060050	03-2003	Pietsch et al.	438/692
*	E	US-2004/0229548	11-2004	Kann et al.	451/028
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	J. Mayer and S. S. Lau, Electronic Materials Science: For Integrated Circuits in Si and GaAs, 1990, Macmillan Publishing, Pp. 30-33 and 44.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.